Beijing University of Posts and Telecommunications

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LABORATORY REPORT TRANSISTOR AMPLIFYING CIRCUIT

INTRODUCTORY SUMMARY

Last week you taught us how to understand the transistor amplifying circuit. Having analyzed the circuit in our lab, I grasped the basic characteristics of the circuit. As you requested, this report will give a summary of the transistor amplifying circuit, along with any problem I had.

As you know, the experiment purpose is to grasp the measuring method of amplifying circuit static state working point and voltage amplification gain.

LAB MATERIALS

The equipment is included digital multitester, DC stabilized voltage power supply, function signal generating device, AC millivolt and double-trace oscilloscope.

LAB PROCEDURE

Once I receive the equipment, I first try to know the role and method of the equipment. My specific lab procedure consisted of these two steps:

Step 1

The measurement of the amplifying circuit static state working point

- a. Judge triode's polarity and the quality with multitester
- b. Connect direct-current power supply, measure V_B , V_E , V_C , R_P with the multitester, and calculate U_{CE} , I_B , I_C

Step 2

Dynamic research

- a. Adjusts R_P to cause V_C to be equal to 6 V
- b. Adjust signal generator's output for the sinusoidal signal of, f=1 kHz, $u_s=500$ mV, and connect A spot, through R_1 , R_2 attenuation 100 times, the signal which the u_i obtain 5 mV
- c. Maintain the signal generating device output signal frequency invariable, increase the signal scope gradually, observe the most greatly not distorted voltage u_o
- d. Maintain u_i =5 mV to be invariable, when idling tune V_C =6 V, and the load is connected to the amplifying circuit
- e. u_i =5 mV, reduce RP, cause $V_C < 4$ V, may observe the saturated distortion, increase R_P , cause $V_C > 9$ V, R_1 is changed from 5.1 K Ω to 510 Ω , may observe to cut off distorts

PROBLEMS ENCOUNTERED

There were some errors, therefore, the problem was the causes of the errors. At the same time, how to discuss the changes of the static working point to the influence of the amplifier output waveform.

CONCLUSION

Through this experiment, I grasp the measuring method of amplifying circuit static state working point and analyze the influence of the static state working point to the amplifier performance. There were some difficulties in the lab, but I solved these with the help of the teacher. I am thankful the teacher's patience to solve.

I will call you this week to discuss our study and any possible follow-up you may wish us to do.

Sincerely, Dong Yaru